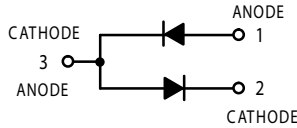
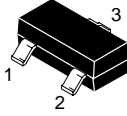
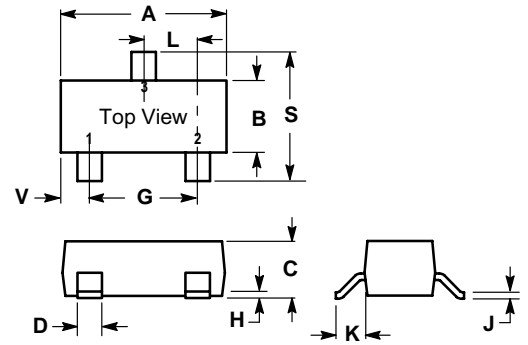


RoHS Compliant Product

A suffix of "-C" specifies halogen & lead-free



SOT-23



Device Marking: A7

SOT-23		
Dim	Min	Max
A	2.800	3.040
B	1.200	1.400
C	0.890	1.110
D	0.370	0.500
G	1.780	2.040
H	0.013	0.100
J	0.085	0.177
K	0.450	0.600
L	0.890	1.020
S	2.100	2.500
V	0.450	0.600
All Dimension in mm		

FEATURES

- Silicon Epitaxial Planar Diodes
- Ultra High Speed
- Low forward voltage : $V_F(3) = 0.9 \text{ V}$ (Typ.)
- Fast reverse recovery time : $t_{rr} = 1.6 \text{ ns}$ (Typ.)
- Small total capacitance : $C_T = 0.9 \text{ pF}$ (Typ.)

MECHANICAL DATA

- Case: SOT-23 Molded Glass
- Terminals : Solder Plated, Solderable Per MIL-STD-750, Method 2026
- Polarity: Indicated by Cathode band
- Mounting position: Any
- Weight: 0.012 grams (approx.)

ABSOLUTE MAXIMUM RATINGS

Rating 25 °C ambient temperature unless otherwise specified.
Single phase half wave, 60Hz, resistive or inductive load.
For capacitive load, derate current by 20%.

TYPE NUMBER	SYMBOL	SCS226K	UNITS
Maximum Recurrent Peak Reverse Voltage	V_{RRM}	85	V
Working Peak Reverse Voltage	V_R	80	V
Maximum Peak Forward Current	I_{FM}	300 (Note1)	mA
Average Forward Current	I_O	100 (Note1)	mA
Peak Forward Surge Current, Single Half Sine-wave Superimposed on Rated Load (JEDEC Method), 10ms	I_{FSM}	2 (Note1)	A
Power Dissipation	P	500	mW
Operating Temperature	T_J	125	°C
Storage Temperature Range	T_{STG}	-55 ~ +125	°C

NOTE:

1. Unit Rating. Total Rating = Unit Rating × 0.7.

● ELECTRICAL CHARACTERISTICS (Ta=25°C)

TYPE NUMBER	TEST CONDITIONS	SYMBOL	Min.	Typ.	Max.	UNITS
Forward Voltage	I _F =1 mA	V _{F(1)}	-	0.60	-	V
	I _F =10 mA	V _{F(2)}	-	0.72	-	
	I _F =100 mA	V _{F(3)}	-	0.90	1.20	
Reverse Current	V _R =30 V	I _{R(1)}	-	-	0.1	μA
	V _R =80 V	I _{R(2)}	-	-	0.5	
Diode Capacitance	V _R =0 V, f=1MHz	C _T	-	0.9	3.0	pF
Reverse Recovery Time	I _F =10 mA, (Fig.1)	t _{rr}	-	1.6	4.0	ns

● RATING AND CHARACTERISTIC CURVES

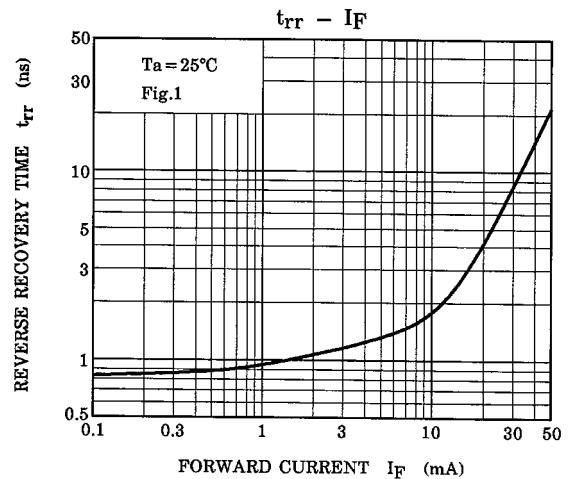
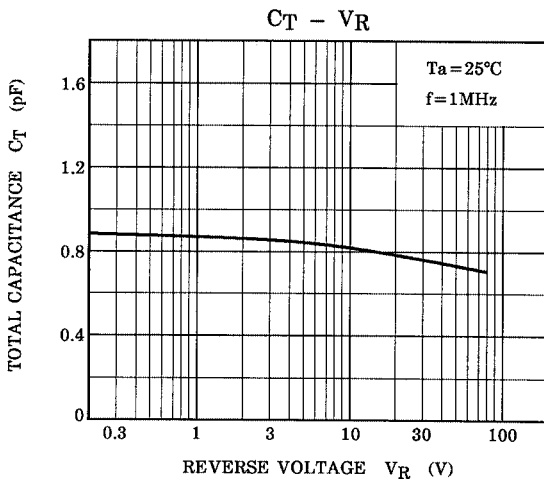
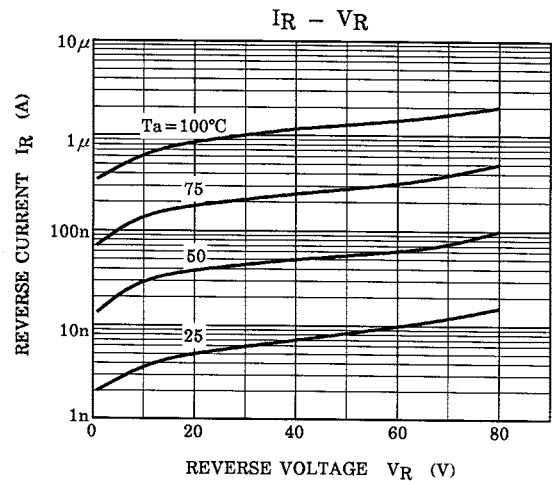
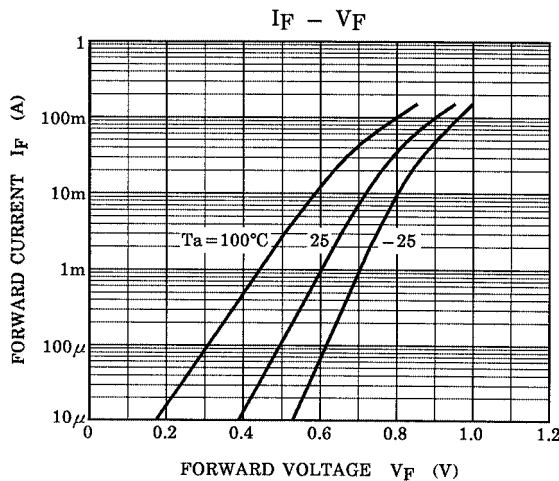


Fig.1 Reverse recovery time (t_{rr}) test circuit

